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²Some elements at Boulder, CO.

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Contents

Articles

Available online http://www.nist.gov/jres

Comparison of the NIST and BIPM Air-Kerma Standards for Measurements in the Low-Energy X-Ray Range	D. T. Burns, P. Lamperti, and M. O'Brien	135
Validation of New Instrumentation for Isotope Dilution Mass Spectrometric Determination of Organic Serum Analytes	P. Ellerbe, C. S. Phinney, L. T. Sniegoski, and M. J. Welch	141
Crystal Structures and Reference Powder Patterns of BaR ₂ ZnO ₅ (R = La, Nd, Sm, Eu, Gd, Dy, Ho, Y, Er, and Tm)	J. A. Kaduk, W. Wong-Ng, W. Greenwood, J. Dillingham, and B. H. Toby	147
Estimation of Concentration and Bonding Environment of Water Dissolved in Common Solvents Using Near Infrared Absorptivity	Brian Dickens and Sabine H. Dickens	173
Near Infrared 45°/0° Reflectance Factor of Pressed Polytetrafluoroethylene (PTFE) Powder	Maria E. Nadal and P. Yvonne Barnes	185
A Fast Method of Transforming Relaxation Functions Into the Frequency Domain	Frederick I. Mopsik	189
Manufacturer's CORBA Interface Testing Toolkit: Overview	David Flater	193

News Briefs

GENERAL DEVELOPMENTS	
Guide to Calibration Service for Capacitance Standards Available New Directory Lists Federal Certification and Related Programs Solidification Sensor for Turbine Blade Castings Developed	
NIST's Rumble Elected President of CODATA New Apparatus Measures Thermal-Barrier Coatings Better A Novel Wear Tester for Biomaterials Evaluation	202
NIST-Developed Validation System for Triple Data Encryption Standard Algorithm Approved as American National Standards Institute (ANSI) Guideline Patent Awarded to NIST Scientist Prefixes for Binary Multiples	203

Medical Physicists Publish Recommendations on Radiochromic Film Dosimetry Nondestructive Radioassay Technique Developed by NIST for Fluid-Filled Balloon Catheters	204
NIST Develops Glow-Discharge Resonance Ionization Mass Spectrometry for Measurement of Environmental Radioactivity Real-Time Characterization of Lithium Transport in Thin-Films	205
NIST Commences Accreditation/Oversight of Commercial Proficiency Testing Study Providers for EPA/States Water Programs New Method Developed for Acquiring Interface Vibrational Spectra	206
Irreversible Magnetic Field Dependence of the Magnetic Structure in GMR Co/Cu Multilayers Experiments Show Feasibility of New Scanning-Probe Microscope Type for High-Resolution Imaging of Fields Encountered in Magnetic Recording NIST Works with Industry to Roadmap Information Technology Needs for the Electronics Industry	207
Standards in Trade Workshops Hosted for Latin America CRADA Signed to Evaluate NIST Ultrasonic Transducer	208
Better Boxes May Mean Reduced Fire Losses Collins Elected ILAC Chair Y2K Help Center Is Open for Business Conference Goal: Making the Web a Lot Less Tangled	209
New Transfer Standard Improves Calibrations for Optical Meters NIST Scientists Demonstrate Highly Directional Atom Laser Doors Opened to New Chemistry Building and NIST's Future	210
1999 National Information Systems Security Conference NIST Proposes Triple DES NIST Facilitates Development of Electronic Books	211
Industry Successfully Evaluating Firewall Products Based on Profiles Developed by NIST and the National Security Agency (NSA) NIST's Interaction Automation Software Used at the South Pole Computer Model Predictions Aid in Decision to Ignite Ship A New Lubricant Concentration Measurement Technique for Pool Boiling	212
Analyzing Neutron Polarization With Polarized ³ He Analyzing Images from Near-Field Optical Microscopy	213
NIST Advanced Radiometer Selected for NASAs Triana Mission High Precision and Sensitivity Achieved Using Midinfrared Cavity Ring Down Spectroscopy First Accurate Vacuum UV Refractive Index Measurements of Calcium Fluoride	214
A Free-Fall Determination of <i>G</i> , the Newtonian Constant of Gravitation Hexapod Kinematic Errors Reduced NIST Researchers Develop Advanced Micromachining Process That Allows Companies Without On-Site Fabrication Facilities to Manufacture MEMS	215

NIST Researchers Develop Standard Reference Data for Important Plasma Processing Gas Databases Now on the Job to Help Keep Gas Flowing	220
	220
New Infrared Spectral Database Introduced to Support Remote Sensing Applications	220
STANDARD REFERENCE DATA	
NIST Standard Reference Material (SRM) Used by the International Atomic Energy Agency Training Programs	
STANDARD REFERENCE MATERIALS	219
Proceedings of the NATO- and NIST-Sponsored Meeting on DNA Damage and Repair Published	219
Optical Spectroscopic Method Found Useful in Determining Phase Separation in Indium Gallium Nitride Films	210
Neutron Scattering Reveals the Mechanism Behind Thermal Contraction	218
Internet-Based Test Service Enables Customers to Interact With NIST Staff While Calibrations Are Performed Refractive Index Profiling of Optical Fibers and Planar Waveguides With Unprecedented Resolution	217
Experimental Results Demonstrate that Power Electronic Interconnect Parasitics Can Be Accurately Characterized With Time Domain Reflectometry Iterative IR Approach for Extracting Values of Intrinsic Optical Constants of Silicon Reduces Uncertainty by a Factor of 10	216